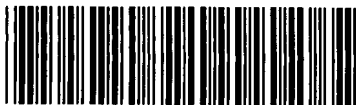


**Search Notes**

Application/Control No.

10/576,553

Examiner

Y. J. Han

Applicant(s)/Patent under  
Reexamination

DERCKX ET AL.

Art Unit

2838

**SEARCHED**

Class	Subclass	Date	Examiner
323	222 225 267 271 272 284 351	11/9/2007	JH

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
PLUS	11/9/2007	JH